

(19) **United States**
(12) **Patent Application Publication** (10) **Pub. No.: US 2024/0178809 A1**
Chang (43) **Pub. Date: May 30, 2024**

(54) **COMPENSATION METHOD FOR CHARACTERISTIC DIFFERENCE OF PHOTOELECTRIC ELEMENT** (52) **U.S. Cl.**
CPC *H03G 3/007* (2013.01); *H03G 3/3015* (2013.01); *H03G 2201/506* (2013.01); *H03G 2201/508* (2013.01)

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(21) Appl. No.: **18/080,179**

(22) Filed: **Dec. 13, 2022**

(30) **Foreign Application Priority Data**
Nov. 29, 2022 (TW) 111145707

Publication Classification

(51) **Int. Cl.**
H03G 3/00 (2006.01)
H03G 3/30 (2006.01)

(57) **ABSTRACT**
A compensation method for a characteristic difference of a photoelectric element is disclosed. The method includes (S1) providing a test substrate with a connector, a photoelectric element and a plurality of gain units, wherein the plurality of gain units are connected in parallel, and each gain unit includes a gain resistor and a disconnection port; (S2) connecting the connector to a test fixture which includes a test resistor and a test control unit, wherein when the test fixture is connected with the connector, the test resistor is electrically connected between the second pin and the third pin; (S3) providing input power to the connector so as to generate a test voltage on the photoelectric element; (S4) selecting the corresponding gain unit according to the test voltage and a classification data table; (S5) driving a production line to connect the first contact and the second contact of the disconnection port of the selected gain unit by the test control unit so that a conduction is formed between the first contact and the second contact of the selected gain unit.

